

# Advanced Process Control of Mix-Product Semiconductor Processes

陳俊宏, Chiou, H. S., Weng, W. T., Tsai S. A.

Mechanical Engineering

Engineering

chen@chu.edu.tw

## Abstract

This paper developed an advanced control technique for mix-product semiconductor processes with measurement delay. The conventional run-to-run process control for single-type-product processes was improved to that for mix-product processes through individually estimating the disturbances induced by tools and products. Simulation results show that, for mix-product processes with measurement delay, the performance of the proposed controller is superior to that of the independent D-EWMA controller.

Keyword : Mix-Product; Semiconductor Processes; Run-To-Run Control; Measurement Delay